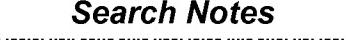


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/628,361	CHANG ET AL.	
Examiner	Art Unit		
HUYEN X. VO	2626		

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Class	Subclass	Date	Examiner
704	231; 240	8/16/2009	HV
704	243; 244	8/16/2009	HV
704	245	8/16/2009	HV